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Application Number	10/721,488					
Filing Date	November 25, 2003					
First Named Inventor	Shiping Guo					
Art Unit	2811 2826					
Examiner Name	Net Yet Assigned Minh-Lo					

Examiner Name Not Yet Assigned Minh-Loan Tran
Attorney Docket Number EMCORE 3.0-081

	U.S. PATENT DOCUMENTS				
Document Nur		Document Number	Publication Date	Name of Patentee or	Pages, Columns, Lines, Where
Examiner Cite Initials* No.		Number-Kind Code ² (#known)	MM-DD-YYYY	Applicant of Cited Document	Relevant Passages or Relevant Figures Appear

		FOREIG	3N PATENT	DOCUMENTS		
Examiner Initials*	Cite No.1	Foreign Patent Document Country Code ³ -Number ⁴ -Kind Code ⁵ (# Innown)	Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document	Pages, Cotumns, Lines, Where Relevant Pessages or Relevant Figures Appear	T°

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		NON PATENT LITERATURE DOCUMENTS	
Examiner Initials	Cite No.1	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published.	T²
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[&]quot;EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

Examiner Signature	Minhloan	Tran	Date Considered	8/05

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			U.S. P.	TENT DOCUMENTS	•
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MLT	BB	-DE 4210402	10-01-1992	Kolchi		
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		NON PATENT LITERATURE DOCUMENTS	
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Attorney Docket Number	EMCORE 3.0-081

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	CE	Manohar, et al., "Characteristics of Microwave Power GaN HEMTs on 4-inch Si Wafers," 2002 IEEE International Microwave Symposium, Seattle WA	
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·	СН	Poschenrieder, et al., "Bright Blue to Orange Photoluminescence Emission from High-Quality InGaN/GaN Multiple-Quantum-Wells on SI(111) Substrates," Applied Physics Letters, Vol. 81, No. 9, pp. 1591-1593 (August 26, 2002)	
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	CK	Tran, et al., "Growth of InGaN/GaN Multiple-Quantum-Well Blue Light-Emitting Diodes on Silicon by Metalorganic Vapor Phase Epitaxy," Applied Physics Letters, Vol. 75, No. 11, pp. 1494-1496 (September 13, 1999)	
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